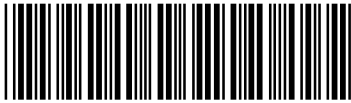


Search Notes

Application/Control No.

10/607,539

Examiner

/BINH K. TIEU/

Applicant(s)/Patent under
Reexamination

FLYNN ET AL.

Art Unit

2614

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	2/29/2008	BKT
455	433	2/29/2008	BKT
455	456	2/29/2008	BKT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST DATABASES SEARCHES	2/29/2008	BKT